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	Methods and Systems For Predicting Software Defects.....	
	FILING November 20, 2003	GROUP TBA

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SGN	US 6,073,107	06/06/00	Minkiewicz et al.			
SGN	US 6,477,471	11/05/02	Hedstrom et al.			
SGN	US 6,546,506	04/08/03	Lewis			
SGN	US 5,446,895	08/29/95	White et al.			
SGN	US 5,655,074	08/05/97	Rauscher			
SGN	US 5,758,061	05/26/98	Plum			
SGN	US 5,903,897	05/11/99	Carrier III et al.			
SGN	US 5,960,196	09/28/99	Carrier III et al.			
SGN	US 6,363,524	03/26/02	Loy			
SGN	US 6,405,364	06/11/02	Bowman-Amuah			
SGN	US 6,513,154	01/28/03	Porterfield			

FOREIGN PATENT DOCUMENTS

DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
					YES	NO

OTHER DOCUMENTS *(Including Author, Title, Date, Pertinent Pages, Etc.)*

SGN			Hudepohl, J.P., et al., "Integrating Metrics and Models For Software Risk Assessment," p. 93, The Seventh International * Symposium on Software Reliability Engineering (ISSRE'96) October 30-November 02, 1996, White Plains, NY (Abstract)
SGN			Levendel, Y., "Reliability Analysis of Large Software Systems: Defect Data Modeling," pp. 141-152, IEEE Transactions on* Software Engineering (Abstract)

EXAMINER /Samuel Neway/	DATE CONSIDERED 07/21/2006
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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SGN		Basili, V., et al., "Understanding and Prediciting the Process of Software Maintenance Releases," 18th International Conference on Software Engineering (ICSE'96), arch 25-29, 1996, p. 464 (Abstract)
SGN		Fenton, N.E., et al., "A Critique of Software Defect Prediction Models," IEEE Transactions on Software Engineering; pp. 675-689 (Abstract)

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